

ITC, CAST, IEEE, and Test Vision Team up on Test Programs at SEMICON West

SEMI

In cooperation with International Test Conference (ITC), Collaborative Alliance for Semiconductor Test (CAST), IEEE, and SEMI, [SEMICON West 2012](#) [1] will feature the latest trends, technology, solutions and methodologies in semiconductor test. In addition to presentations by industry experts in conference TechXPOTs, an expanded Test Vision 2020 Conference will again be held in conjunction with SEMICON West, providing critical information and networking opportunities for test industry buyers, managers, developers and technologists.

Test Sessions at SEMICON West

At the TechXPOT session in Moscone Center's North Hall on Tuesday, July 10, the afternoon session on [Adding Value through Yield and Better Data Management](#) [2] will examine how leading IC manufacturers and OSATs are better leveraging data to improve yield, decrease test time and perform effective root cause analysis to lower test costs. Real solutions and techniques in Adaptive Test, closed-loop data management, DFM-aware and layout-aware diagnosis tools, 3D-IC Test, and other areas will be discussed by leading experts from Mentor Graphics, Texas Instruments, Optimal Test, Teradyne, Camstar Systems and Advantest.

On Wednesday, July 11, in a first-ever collaboration with [International Test Conference](#) [3], leading peer-recognized academic and technical presentations on semiconductor test will be presented at the TechXPOT North on the exhibition floor at SEMICON West. Leading papers on cell aware analysis, systematic defect analysis, end-to-end error correction, and timing variation tolerance will be presented by speakers from Mentor Graphics, Carnegie Mellon University, University of California at Santa Barbara, and the China Academy of Sciences.

Test Vision 2020 Expands

Co-organized by SEMI and IEEE, [Test Vision 2020](#) [4] (formerly ATE Vision 2020) has emerged as the premier workshop in semiconductor test and Automated Test Equipment. Attracting executive attendance from a broad cross-section of the semiconductor community, the workshop features a compelling line-up of papers, keynotes and panel participation from leaders in the industry. This year's workshop will expand to one and one-half days, beginning on Wednesday, July 11 at 3:00pm and continuing until 5:00pm on Thursday, July 12. Experts and executives from chip manufacturers, EDA companies, fabless semiconductor companies, outsourced assembly and test firms, and other industry stakeholders will discuss the future of semiconductor testing, and network with colleagues in a friendly, interactive environment.

SEMICON West Goes Mobile

SEMICON West has introduced a new mobile app for attendees, bringing virtually all of the show content to iPhones, iPads, and Android devices. The SEMICON West mobile app, sponsored by Applied Materials, acts as a portable guide to the event, with access to complete exhibitor listings, floor plans, program schedules, speakers, and local information. The new app is available now from the iTunes Store and Google Play. More information about the app is available at:

www.semiconwest.org/Participate/MobileApp [5]

About SEMI

SEMI is the global industry association serving the nano- and microelectronics manufacturing supply chains. SEMI member companies are the engine of the future, enabling smarter, faster and more economical products that improve our lives. Since 1970, SEMI has been committed to helping members grow more profitably, create new markets and meet common industry challenges. SEMI maintains offices in Beijing, Bengaluru, Berlin, Brussels, Grenoble, Hsinchu, Moscow, San Jose, Seoul, Shanghai, Singapore, Tokyo, and Washington, D.C. For more information, visit www.semi.org [6].

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Links:

[1] <http://www.semiconwest.org/>

[2] <http://www.semiconwest.org/node/8516>

[3] <http://www.semiconwest.org/node/8521>

[4] <http://www.semiconwest.org/node/8601>

[5] <http://www.semiconwest.org/Participate/MobileApp>

[6] <http://www.semi.org/>

[7] <http://www.semi.org/en/node/mailto:dgeiger@semi.org>